

Search Notes

Application/Control No.

10/803,536

Examiner

Evan Dzierzynski

Applicant(s)/Patent under
Reexamination

HAYASHI ET AL.

Art Unit

2875

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 362 | 466 | 6/12/2006 | ED |
| | 465 | 6/12/2006 | ED |
| | 460 | 6/12/2006 | ED |
| | 464 | 6/12/2006 | ED |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| EAST word search | 6/12/2006 | ED |
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